

# MM58274C

*MM58274C Microprocessor Compatible Real Time Clock*



Literature Number: SNOS618A

## MM58274C Microprocessor Compatible Real Time Clock

### General Description

The MM58274C is fabricated using low threshold metal gate CMOS technology and is designed to operate in bus oriented microprocessor systems where a real time clock and calendar function are required. The on-chip 32.768 kHz crystal controlled oscillator will maintain timekeeping down to 2.2V to allow low power standby battery operation. This device is pin compatible with the MM58174A but continues timekeeping up to tens of years. The MM58274C is a direct replacement for the MM58274 offering improved Bus access cycle times.

### Applications

- Point of sale terminals
- Teller terminals
- Word processors
- Data logging
- Industrial process control

### Features

- Same pin-out as MM58174A, MM58274B, and MM58274
- Timekeeping from tenths of seconds to tens of years in independently accessible registers
- Leap year register
- Hours counter programmable for 12 or 24-hour operation
- Buffered crystal frequency output in test mode for easy oscillator setting
- Data-changed flag allows simple testing for time rollover
- Independent interrupting time with open drain output
- Fully TTL compatible
- Low power standby operation (10  $\mu$ A at 2.2V)
- Low cost 16-pin DIP and 20-pin PCC

### Block Diagram

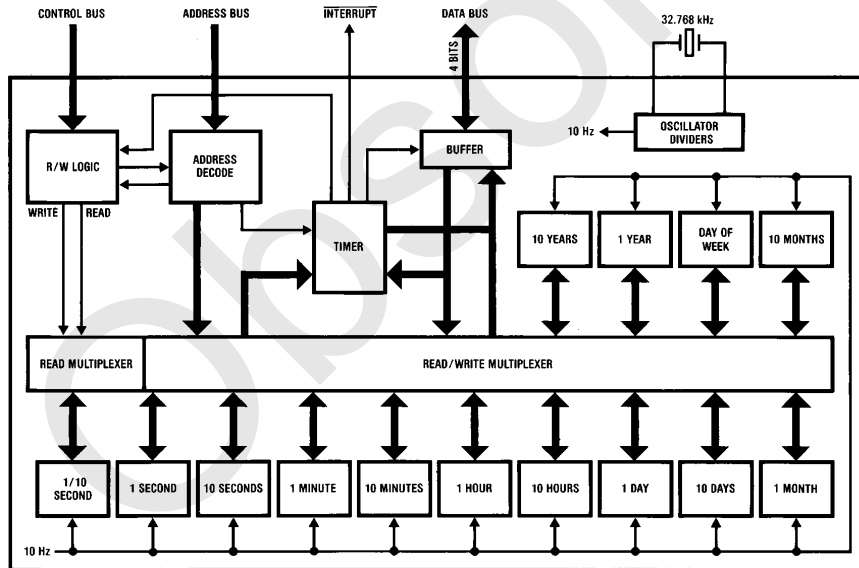


FIGURE 1

TL/F/11219-1

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## Absolute Maximum Ratings (Note 1)

If Military/Aerospace specified devices are required, please contact the National Semiconductor Sales Office/Distributors for availability and specifications.

DC Input or Output Voltage	-0.3V to $V_{DD} + 0.3V$
DC Input or Output Diode Current	$\pm 5.0$ mA
Storage Temperature, $T_{STG}$	-65°C to +150°C
Supply Voltage, $V_{DD}$	6.5V
Power Dissipation, $P_D$	500 mW
Lead Temperature (Soldering, 10 seconds)	260°

## Operating Conditions

	Min	Max	Units
Operating Supply Voltage	4.5	5.5	V
Standby Mode Supply Voltage	2.2	5.5	V
DC Input or Output Voltage	0	$V_{DD}$	V
Operating Temperature Range	-40	85	°C

## Electrical Characteristics $V_{DD} = 5V \pm 10\%$ , $T = -40^\circ\text{C}$ to $+85^\circ\text{C}$ unless otherwise stated.

Symbol	Parameter	Conditions	Min	Typ	Max	Units
$V_{IH}$	High Level Input Voltage (except XTAL IN)		2.0			V
$V_{IL}$	Low Level Input Voltage (except XTAL IN)				0.8	V
$V_{OH}$	High Level Output Voltage (DB0-DB3)	$I_{OH} = -20 \mu\text{A}$ $I_{OH} = -1.6 \text{ mA}$	$V_{DD} - 0.1$ 3.7			V V
$V_{OH}$	High Level Output Voltage (INT)	$I_{OH} = -20 \mu\text{A}$ (In Test Mode)	$V_{DD} - 0.1$			V
$V_{OL}$	Low Level Output Voltage (DB0-DB3, INT)	$I_{OL} = 20 \mu\text{A}$ $I_{OL} = 1.6 \text{ mA}$			0.1 0.4	V V
$I_{IL}$	Low Level Input Current (AD0-AD3, DB0-DB3)	$V_{IN} = V_{SS}$ (Note 2)	-5		-80	$\mu\text{A}$
$I_{IL}$	Low Level Input Current ( $\overline{WR}$ , $\overline{RD}$ )	$V_{IN} = V_{SS}$ (Note 2)	-5		-190	$\mu\text{A}$
$I_{IL}$	Low Level Input Current ( $\overline{CS}$ )	$V_{IN} = V_{SS}$ (Note 2)	-5		-550	$\mu\text{A}$
$I_{OZH}$	Output High Level Leakage Current (INT)	$V_{OUT} = V_{DD}$			2.0	$\mu\text{A}$
$I_{DD}$	Average Supply Current	All $V_{IN} = V_{CC}$ or Open Circuit $V_{DD} = 2.2V$ (Standby Mode) $V_{DD} = 5.0V$ (Active Mode)		4	10 1	$\mu\text{A}$ mA
$C_{IN}$	Input Capacitance			5	10	pF
$C_{OUT}$	Output Capacitance	(Outputs Disabled)		10		pF

**Note 1:** Absolute Maximum Ratings are those values beyond which damage to the device may occur. All voltages referenced to ground unless otherwise noted.







**Note 2:** The DB0-DB3 and AD0-AD3 lines all have active P-channel pull-up transistors which will source current. The  $\overline{CS}$ ,  $\overline{RD}$ , and  $\overline{WR}$  lines have internal pull-up resistors to  $V_{DD}$ .

## AC Switching Characteristics

**READ TIMING: DATA FROM PERIPHERAL TO MICROPROCESSOR**  $V_{DD} = 5V \pm 0.5V$ ,  $C_L = 100$  pF

Symbol	Parameter	Commercial Specification			Units
		$T_A = -40^\circ\text{C to } +85^\circ\text{C}$			
		Min	Typ	Max	
$t_{AD}$	Address Bus Valid to Data Valid		390	650	ns
$t_{CSD}$	Chip Select On to Data Valid		140	300	ns
$t_{RD}$	Read Strobe On to Data Valid		140	300	ns
$t_{RW}$	Read Strobe Width (Note 3, Note 7)			DC	
$t_{RA}$	Address Bus Hold Time from Trailing Edge of Read Strobe	0			ns
$t_{CSH}$	Chip Select Hold Time from Trailing Edge of Read Strobe	0			ns
$t_{RH}$	Data Hold Time from Trailing Edge of Read Strobe	70	160		ns
$t_{HZ}$	Time from Trailing Edge of Read Strobe Until O/P Drivers are TRI-STATE®			250	ns

**WRITE TIMING: DATA FROM MICROPROCESSOR TO PERIPHERAL**  $V_{DD} = 5V \pm 0.5V$

Symbol	Parameter	Commercial Specification			Units
		$T_A = -40^\circ\text{C to } +85^\circ\text{C}$			
		Min	Typ	Max	
$t_{AW}$	Address Bus Valid to Write Strobe  (Note 4, Note 6)	400	125		ns
$t_{CSW}$	Chip Select On to Write Strobe 	250	100		ns
$t_{DW}$	Data Bus Valid to Write Strobe 	400	220		ns
$t_{WW}$	Write Strobe Width (Note 6)	250	95		ns
$t_{WCS}$	Chip Select Hold Time Following Write Strobe 	0			ns
$t_{WA}$	Address Bus Hold Time Following Write Strobe 	0			ns
$t_{WD}$	Data Bus Hold Time Following Write Strobe 	100	35		ns
$t_{AWS}$	Address Bus Valid Before Start of Write Strobe	70	20		ns

**Note 3:** Except for special case restriction: with interrupts programmed, max read strobe width of control register (ADDR 0) is 30 ms. See section on Interrupt Programming.

**Note 4:** All timings measured to the trailing edge of write strobe (data latched by the trailing edge of  $\overline{WR}$ ).

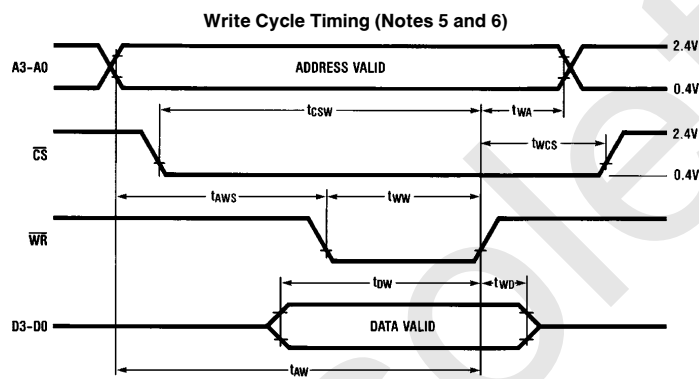
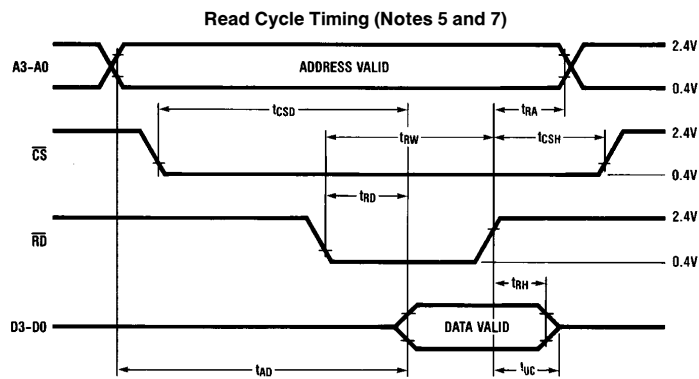
**Note 5:** Input test waveform peak voltages are 2.4V and 0.4V. Output signals are measured to their 2.4V and 0.4V levels.

**Note 6:** Write strobe as used in the Write Timing Table is defined as the period when both chip select and write inputs are low, i.e.,  $\overline{WS} = \overline{CS} + \overline{WR}$ . Hence write strobe commences when both signals are low, and terminates when the first signal returns high.

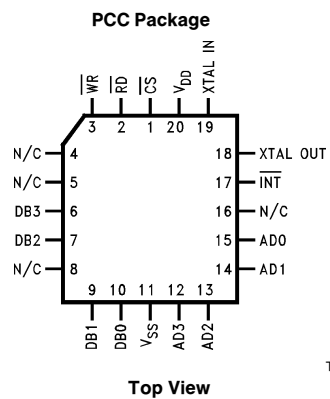
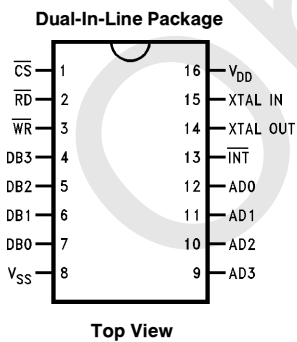
**Note 7:** Read strobe as used in the Read Timing Table is defined as the period when both chip select and read inputs are low, i.e.,  $\overline{RS} = \overline{CS} + \overline{RD}$ .

**Note 8:** Typical numbers are at  $V_{CC} = 5.0V$  and  $T_A = 25^\circ\text{C}$ .

## Switching Time Waveforms



## Connection Diagrams



**FIGURE 2**

Order Number MM58274CJ, MM58274CN or MM58274CV  
See NS Package J16A, N16A, or V20A



## Functional Description (Continued)

device which are synchronously clocked by this signal. All time data and data-changed flag change on the falling edge of the clock setting pulse.

### Data-Changed Flag

The data-changed flag is set by the clock setting pulse to indicate that the time data has been altered since the clock was last read. This flag occupies bit 3 of the control register where it can be tested by the processor to sense data-changed. It will be reset by a read of the control register. See the section, "Methods of Device Operation", for suggested clock reading techniques using this flag.

### Seconds Counters

There are three counters for seconds:

- a) tenths of seconds
- b) units of seconds
- c) tens of seconds.

The registers are accessed at the addresses shown in Table I. The tenths of seconds register is reset to 0 when the clock start/stop bit (bit 2 of the control register) is set to logic 1. The units and tens of seconds are set up by the processor, giving time setting to the nearest second. All three registers can be read by the processor for time output.

### Minutes Counters

There are two minutes counters:

- a) units of minutes
- b) tens of minutes.

Both registers may be read to or written from as required.

### Hours Counters

There are two hours counters:

- a) units of hours
- b) tens of hours.

Both counters may be accessed for read or write operations as desired.

In 12-hour mode, the tens of hours register has only one active bit and the top three bits are set to logic 0. Data bit 1 of the clock setting register is the AM/PM indicator; logic 0 indicating AM, logic 1 for PM.

When 24-hour mode is programmed, the tens of hours register reads out two bits of data and the two most significant bits are set to logic 0. There is no AM/PM indication and bit 1 of the clock setting register will read out a logic 0.

In both 12/24-hour modes, the units of hours will read out four active data bits. 12 or 24-hour mode is selected by bit 0 of the clock setting register, logic 0 for 12-hour mode, logic 1 for the 24-hour mode.

### Days Counters

There are two days counters:

- a) units of days
- b) tens of days.

The days counters will count up to 28, 29, 30 or 31 depending on the state of the months counters and the leap year counter. The microprocessor has full read/write access to these registers.

### Months Counters

There are two months counters:

- a) units of months
- b) tens of months.

Both these counters have full read/write access.

### Years Counters

There are two years counters:

- a) units of years
- b) tens of years.

Both these counters have full read/write access. The years will count up to 99 and roll over to 00.

**TABLE I. Address Decoding of Real-Time Clock Internal Registers**

Register Selected	Address (Binary)				(Hex)	Access
	AD3	AD2	AD1	AD0		
0 Control Register	0	0	0	0	0	Split Read and Write
1 Tenths of Seconds	0	0	0	1	1	Read Only
2 Units Seconds	0	0	1	0	2	R/W
3 Tens Seconds	0	0	1	1	3	R/W
4 Units Minutes	0	1	0	0	4	R/W
5 Tens Minutes	0	1	0	1	5	R/W
6 Unit Hours	0	1	1	0	6	R/W
7 Tens Hours	0	1	1	1	7	R/W
8 Units Days	1	0	0	0	8	R/W
9 Tens Days	1	0	0	1	9	R/W
10 Units Months	1	0	1	0	A	R/W
11 Tens Months	1	0	1	1	B	R/W
12 Units Years	1	1	0	0	C	R/W
13 Tens Years	1	1	0	1	D	R/W
14 Day of Week	1	1	1	0	E	R/W
15 Clock Setting/ Interrupt Registers	1	1	1	1	F	R/W

## Functional Description (Continued)

### Day of Week Counter

The day of week counter increments as the time rolls from 23:59 to 00:00 (11:59 PM to 12:00 AM in 12-hour mode). It counts from 1 to 7 and rolls back to 1. Any day of the week may be specified as day 1.

### Clock Setting Register/Interrupt Register

The interrupt select bit in the control register determines which of these two registers is accessible to the processor at address 15. Normal clock and interrupt timing operations will always continue regardless of which register is selected onto the bus. The layout of these registers is shown in Table II.

The clock setting register is comprised of three separate functions:

- leap year counter: bits 2 and 3
- AM/PM indicator: bit 1
- 12-hour mode set: bit 0 (see Table IIA).

The leap year counter is a 2-stage binary counter which is clocked by the months counter. It changes state as the time rolls over from 11:59 on December 31 to 00:00 on January 1.

The counter should be loaded with the 'number of years since last leap year' e.g., if 1980 was the last leap year, a clock programmed in 1983 should have 3 stored in the leap year counter. If the clock is programmed during a leap year, then the leap year counter should be set to 0. The contents of the leap year counter can be read by the  $\mu$ P.

The AM/PM indicator returns a logic 0 for AM and a logic 1 for PM. It is clocked when the hours counter rolls from 11:59 to 12:00 in 12-hour mode. In 24-hour mode this bit is set to logic 0.

The 12/24-hour mode set determines whether the hours counter counts from 1 to 12 or from 0 to 23. It also controls the AM/PM indicator, enabling it for 12-hour mode and forcing it to logic 0 for the 24-hour mode. The 12/24-hour mode bit is set to logic 0 for 12-hour mode and it is set to logic 1 for 24-hour mode.

**IMPORTANT NOTE:** Hours mode and AM/PM bits cannot be set in the same write operation. See the section on Initialization (Methods of Device Operation) for a suggested setting routine.

All bits in the clock setting register may be read by the processor.

The interrupt register controls the operation of the timer for interrupt output. The processor programs this register for single or repeated interrupts at the selected time intervals.

The lower three bits of this register set the time delay period that will occur between interrupts. The time delays that can be programmed and the data words that select these are outlined in Table IIB.

Data bit 3 of the interrupt register sets for either single or repeated interrupts; logic 0 gives single mode, logic 1 sets for repeated mode.

Using the interrupt is described in the Device Operation section.

**TABLE IIA. Clock Setting Register Layout**

Function	Data Bits Used				Comments	Access
	DB3	DB2	DB1	DB0		
Leap Year Counter	X	X			0 Indicates a Leap Year 0 = AM 1 = PM	R/W
AM/PM Indicator (12-Hour Mode)			X			R/W
12/24-Hour Select Bit				X	0 = 12-Hour Mode 1 = 24-Hour Mode	R/W

**TABLE IIB. Interrupt Control Register**

Function	Comments	Control Word			
		DB3	DB2	DB1	DB0
No Interrupt	Interrupt output cleared, start/stop bit set to 1.	X	0	0	0
0.1 Second		0/1	0	0	1
0.5 Second		0/1	0	1	0
1 Second		0/1	0	1	1
5 Seconds	DB3 = 0 for single interrupt	0/1	1	0	0
10 Seconds	DB3 = 1 for repeated interrupt	0/1	1	0	1
30 Seconds		0/1	1	1	0
60 Seconds		0/1	1	1	1

Timing Accuracy: single interrupt mode (all time delays):  $\pm 1$  ms  
 Repeated Mode:  $\pm 1$  ms on initial timeout, thereafter synchronous with first interrupt (i.e., timing errors do not accumulate).



## Functional Description (Continued)

### Control Register

There are three registers which control different operations of the clock:

- a) the clock setting register
- b) the interrupt register
- c) the control register.

The clock setting and interrupt registers both reside at address 15, access to one or the other being controlled by the interrupt select bit; data bit 1 of the control register.

The clock setting register programs the timekeeping of the clock. The 12/24-hour mode select and the AM/PM indicator for 12-hour mode occupy bits 0 and 1, respectively. Data bits 2 and 3 set the leap year counter.

The interrupt register controls the operation of the interrupt timer, selecting the required delay period and either single or repeated interrupt.

The control register is responsible for controlling the operations of the clock and supplying status information to the processor. It appears as two different registers; one with write only access and one with read only access.

The write only register consists of a bank of four latches which control the internal processes of the clock.

The read only register contains two output data latches which will supply status information for the processor. Table III shows the mapping of the various control latches and status flags in the control register. The control register is located at address 0.

The write only portion of the control register contains four latches:

A logic 1 written into the test bit puts the device into test mode. This allows setting of the oscillator frequency as well as rapid testing of the device registers, if required. A more complete description is given in the Test Mode section. For normal operation the test bit is loaded with logic 0.

The clock start/stop bit stops the timekeeping of the clock and resets to 0 the tenths of seconds counter. The time of day may then be written into the various clock registers and the clock restarted synchronously with an external time source. Timekeeping is maintained thereafter.

A logic 1 written to the start/stop bit halts clock timing. Timing is restarted when the start/stop bit is written with a logic 0.

The interrupt select bit determines which of the two registers mapped onto address 15 will be accessed when this address is selected.

A logic 0 in the interrupt select bit makes the clock setting register available to the processor. A logic 1 selects the interrupt register.

The interrupt start/stop bit controls the running of the interrupt timer. It is programmed in the same way as the clock start/stop bit; logic 1 to halt the interrupt and reset the timer, logic 0 to start interrupt timing.

When no interrupt is programmed (interrupt control register set to 0), the interrupt start/stop bit is automatically set to a logic 1. When any new interrupt is subsequently programmed, timing will not commence until the start/stop bit is loaded with 0.

In the single interrupt mode, interrupt timing stops when a timeout occurs. The processor restarts timing by writing logic 0 into the start/stop bit.

In repeated interrupt mode the interrupt timer continues to count with no intervention by the processor necessary.

Interrupt timing may be stopped in either mode by writing a logic 1 into the interrupt start/stop bit. The timer is reset and can be restarted in the normal way, giving a full time delay period before the next interrupt.

In general, the control register is set up such that writing 0's into it will start anything that is stopped, pull the clock out of test mode and select the clock setting register onto the bus. In other words, writing 0 will maintain normal clock operation and restart interrupt timing, etc.

The read only portion of the control register has two status outputs:

Since the MM58274C keeps real time, the time data changes asynchronously with the processor and this may occur while the processor is reading time data out of the clock.

Some method of warning the processor when the time data has changed must thus be included. This is provided for by the data-changed flag located in bit 3 of the control register. This flag is set by the clock setting pulse which also clocks the time registers. Testing this bit can tell the processor whether or not the time has changed. The flag is cleared by a read of the control register but not by any write operations. No other register read has any effect on the state of the data-changed flag.

Data bit 0 is the interrupt flag. This flag is set whenever the interrupt timer times out, pulling the interrupt output low. In a polled interrupt routine the processor can test this flag to determine if the MM58274C was the interrupting device. This interrupt flag and the interrupt output are both cleared by a read of the control register.

TABLE III. The Control Register Layout

Access (addr0)	DB3	DB2	DB1	DB0
Read From:	Data-Changed Flag	0	0	Interrupt Flag
Write To:	Test 0 = Normal 1 = Test Mode	Clock Start/Stop 0 = Clock Run 1 = Clock Stop	Interrupt Select 0 = Clock Setting Register 1 = Interrupt Register	Interrupt Start/Stop 0 = Interrupt Run 1 = Interrupt Stop

## Functional Description (Continued)

Both of the flags and the interrupt output are reset by the trailing edge of the read strobe. The flag information is held latched during a control register read, guaranteeing that stable status information will always be read out by the processor.

Interrupt timeout is detected and stored internally if it occurs during a read of the control register, the interrupt output will then go low only after the read has been completed.

A clock setting pulse occurring during a control register read will *not* affect the data-changed flag since time data read out before or after the control read will not be affected by the time change.

### METHODS OF DEVICE OPERATION

#### Test Mode

National Semiconductor uses test mode for functionally testing the MM58274C after fabrication and again after packaging. Test mode can also be used to set up the oscillator frequency when the part is first commissioned.

Figure 4 shows the internal clock connections when the device is written into test mode. The 32.768 kHz oscillator is gated onto the interrupt output to provide a buffered output for initial frequency setting. This signal is driven from a TRI-STATE output buffer, enabling easy oscillator setting in systems where interrupt is not normally used and there is no external resistor on the pin.

If an interrupt is programmed, the 32.768 kHz output is switched off to allow high speed testing of the interrupt timer. The interrupt output will then function as normal.

The clock start/stop bit can be used to control the fast clocking of the time registers as shown in Figure 4.

#### Initialization

When it is first installed and power is applied, the device will need to be properly initialized. The following operation steps are recommended when the device is set up (all numbers are decimal):

1) Disable interrupt on the processor to allow oscillator setting. Write 15<sub>10</sub> into the control register: *The clock and interrupt start/stop bits are set to 1, ensuring that the clock and interrupt timers are both halted. Test mode and the interrupt register are selected.*

2) Write 0 to the interrupt register: *Ensure that there are no interrupts programmed and that the oscillator will be gated onto the interrupt output.*

3) Set oscillator frequency: *All timing has been halted and the oscillator is buffered out onto the interrupt line.*

4) Write 5 to the control register: *The clock is now out of test mode but is still halted. The clock setting register is now selected by the interrupt select bit.*

5) Write 0001 to all registers. This ensures starting with a valid BCD value in each register.

6) Set 12/24 Hours Mode: *Write to the clock setting register to select the hours counting mode required.*

7) Load Real-Time Registers: *All time registers (including Leap Years and AM/PM bit) may now be loaded in any order. Note that when writing to the clock setting register to set up Leap Years and AM/PM, the Hours Mode bit must not be altered from the value programmed in step 5.*

8) Write 0 to the control register: *This operation finishes the clock initialization by starting the time. The final control register write should be synchronized with an external time source.*

In general, timekeeping should be halted before the time data is altered in the clock. The data can, however, be altered at any time if so desired. Such may be the case if the user wishes to keep the clock corrected without having to stop and restart it; i.e., winter/summer time changing can be accomplished without halting the clock. This can be done in software by sensing the state of the data-changed flag and only altering time data just after the time has rolled over (data-changed flag set).

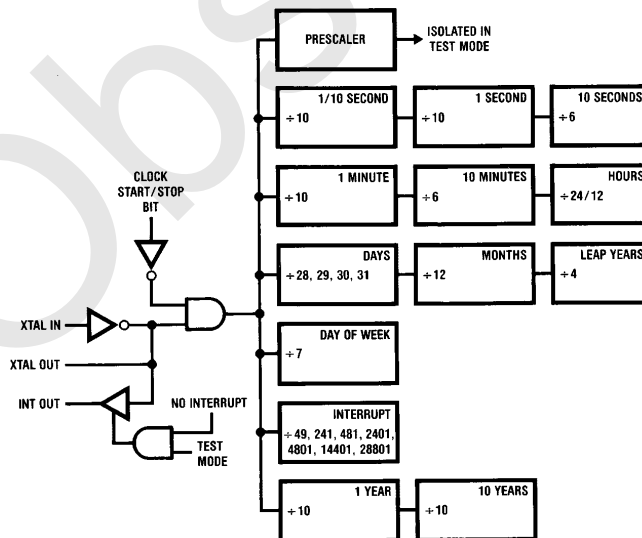


FIGURE 4. Test Mode Organization

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## Functional Description (Continued)

### Reading the Time Registers

Using the data-changed flag technique supports microprocessors with block move facilities, as all the necessary time data may be read sequentially and then tested for validity as shown below.

- 1) Read the control register, address 0: *This is a dummy read to reset the data-changed flag (DCF) prior to reading the time registers.*
- 2) Read time registers: *All desired time registers are read out in a block.*
- 3) Read the control register and test DCF: *If DCF is cleared (logic 0), then no clock setting pulses have after occurred since step 1. All time data is guaranteed good and time reading is complete.*

If DCF is set (logic 1), then a time change has occurred since step 1 and time data may not be consistent. Repeat steps 2 and 3 until DCF is clear. The control read of step 3 will have reset DCF, automatically repeating the step 1 action.

### Interrupt Programming

The interrupt timer generates interrupts at time intervals which are programmed into the interrupt register. A single interrupt after delay or repeated interrupts may be programmed. Table IIB lists the different time delays and the data words that select them in the interrupt register.

Once the interrupt register has been used to set up the delay time and to select for single or repeat, it takes no further part in the workings of the interrupt system. All activity by the processor then takes place in the control register.

Initializing:

- 1) Write 3 to the control register (AD0): *Clock timing continues, interrupt register selected and interrupt timing stopped.*
- 2) Write interrupt control word to address 15: *The interrupt register is loaded with the correct word (chosen from Table IIB) for the time delay required and for single or repeated interrupts.*
- 3) Write 0 or 2 to the control register: *Interrupt timing commences. Writing 0 selects the clock setting register onto the data bus; writing 2 leaves the interrupt register selected. Normal timekeeping remains unaffected.*

On interrupt:

Read the control register and test for Interrupt Flag (bit 0).

If the flag is cleared (logic 0), then the device is not the source of the interrupt.

If the flag is set (logic 1), then the clock did generate an interrupt. The flag is reset and the interrupt output is cleared by the control register read that was used to test for interrupt.

Single Interrupt Mode:

When appropriate, write 0 or 2 to the control register to restart the interrupt timer.

Repeated Interrupt Mode:

Timing continues, synchronized with the control register write which originally started interrupt timing. No further intervention is necessary from the processor to maintain timing.

In either mode interrupt timing can be stopped by writing 1 into the control register (interrupt start/stop set to 1). Timing for the full delay period recommences when the interrupt start/stop bit is again loaded with 0 as normal.

**IMPORTANT NOTE:** Using the interrupt timer places a constraint on the maximum Read Strobe width which may be applied to the clock. Normally all registers may be read from with a  $t_{RW}$  down to DC (i.e.,  $\overline{CS}$  and  $\overline{RD}$  held continuously low). When the interrupt timer is active however, the maximum read strobe width that can be applied to the control register (Addr 0) is 30 ms.

This restriction is to allow the interrupt timer to properly reset when it times out. Note that it only affects reading of the control register—all other addresses in the clock may be accessed with DC read strobes, regardless of the state of the interrupt timer. Writes to any address are unaffected.

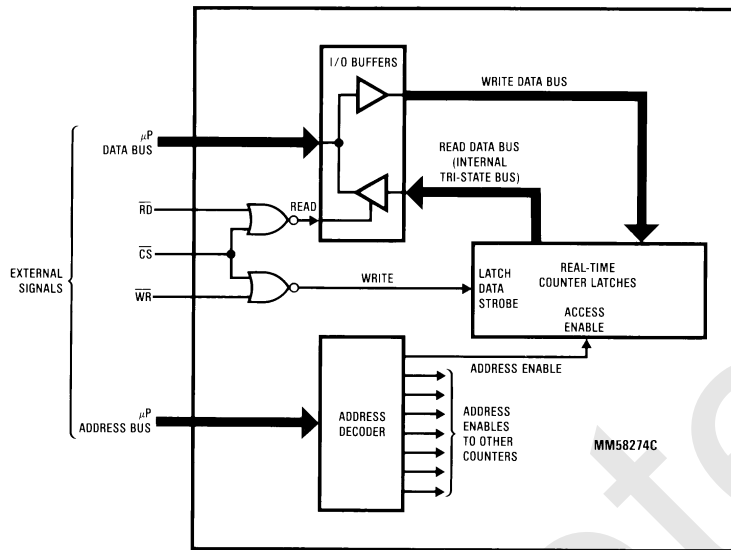
### NOTES ON AC TIMING REQUIREMENTS

Although the Switching Time Waveforms show Microbus control signals used for clock access, this does not preclude the use of the MM58274C in other non-Microbus systems. Figure 5 is a simplified logic diagram showing how the control signals are gated internally to control access to the clock registers. From this diagram it is clear that  $\overline{CS}$  could be used to generate the internal data transfer strobes, with  $\overline{RD}$  and  $\overline{WR}$  inputs set up first. This situation is illustrated in Figure 6.

The internal data busses of the MM58274C are fully CMOS, contributing to the flexibility of the control inputs. When determining the suitability of any given control signal pattern for the MM58274C the timing specifications in AC Switching Characteristics should be examined. As long as these timings are met (or exceeded) the MM58274C will function correctly.

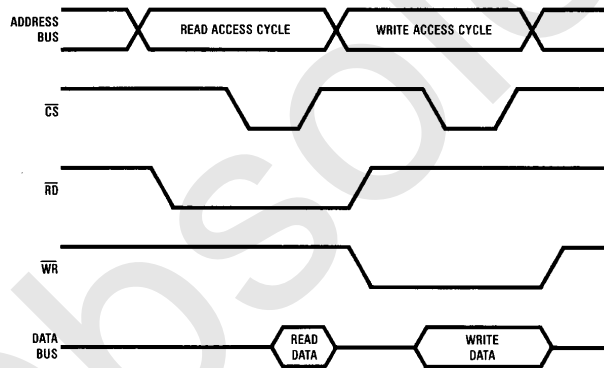
When the MM58274C is connected to the system via a peripheral port, the freedom from timing constraints allows for very simple control signal generation, as in Figure 7. For reading (Figure 7a), Address,  $\overline{CS}$  and  $\overline{RD}$  may be activated simultaneously and the data will be available at the port after  $t_{AD-max}$  (650 ns). For writing (Figure 7b), the address and data may be applied simultaneously; 70 ns later  $\overline{CS}$  and  $\overline{WR}$  may be strobed together.

**Functional Description** (Continued)



**FIGURE 5. MM58274C Microprocessor Interface Diagram**

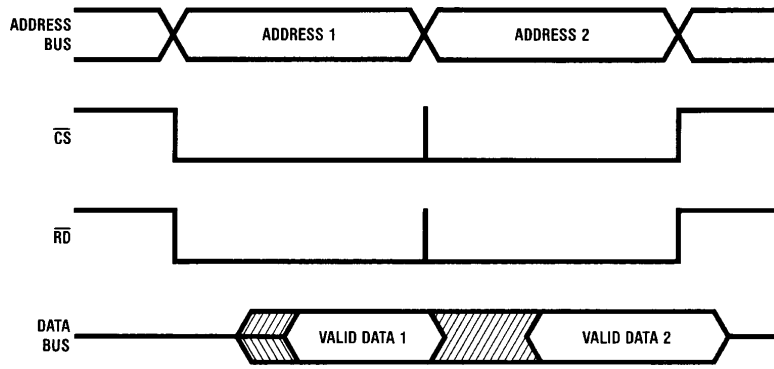
TL/F/11219-8



**FIGURE 6. Valid MM58274C Control Signals Using Chip Select Generated Access Strokes**

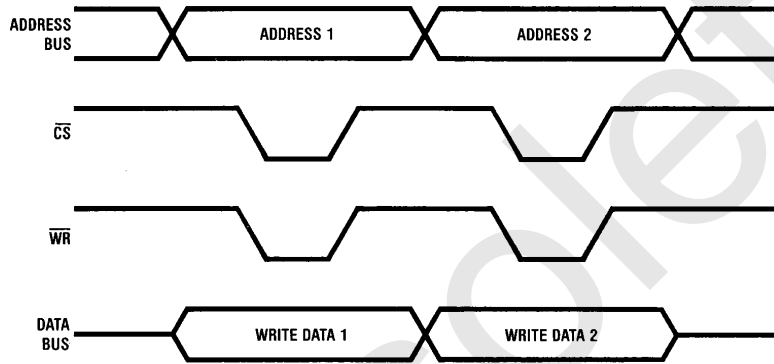
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### Functional Description (Continued)



a. Port Generated Read Access—2 Addresses Read Out

TL/F/11219-10



b. Port Generated Write Access—2 Addresses Written To

TL/F/11219-11

FIGURE 7. Simple Port Generated Control Signals

## Functional Description (Continued)

### APPLICATION HINTS

#### Time Reading Using Interrupt

In systems such as point of sale terminals and data loggers, time reading is usually only required on a random demand basis. Using the data-changed flag as outlined in the section on methods of operation is ideal for this type of system. Some systems, however, need to sense a change in real time; e.g., industrial timers/process controllers, TV/VCR clocks, any system where real time is displayed.

The interrupt timer on the MM58274C can generate interrupts synchronously with the time registers changing, using software to provide the initial synchronization.

In single interrupt mode the processor is responsible for initiating each timing cycle and the timed period is accurate to  $\pm 1$  ms.

In repeated interrupt mode the period from the initial processor start to the first timeout is also only accurate to  $\pm 1$  ms. The following interrupts maintain accurate delay periods relative to the first timeout. Thus, to utilize interrupt to control time reading, we will use repeated interrupt mode.

In repeated mode the time period between interrupts is exact, which means that timeouts will always occur at the same point relative to the internal clock setting pulses. The case for 0.1s interrupts is shown in *Figure A-1*. The same is true for other delay periods, only there will be more clock setting pulses between each interrupt timeout. If we set up the interrupt timer so that interrupt always times out just after the clock setting pulse occurs (*Figure A-2*), then there is no need to test the data-changed flag as we know that the time data has just changed and will not alter again for another 100 ms.

This can be achieved as outlined below:

- 1) Follow steps 1 and 2 of the section on interrupt programming. In step 2 set up for repeated interrupt.

- 2) Read control register AD0: *This is a dummy read to reset the data-changed flag.*

- 3) Read control register AD0 until data-changed flag is set.

- 4) Write 0 or 2 to control register. Interrupt timing commences.

#### Time Reading with Very Slow Read Cycles

If a system takes longer than 100 ms to complete reading of all the necessary time registers (e.g., when CMOS processors are used) or where high level interpreted language routines are used, then the data-changed flag will always be set when tested and is of no value. In this case, the time registers themselves must be tested to ensure data accuracy.

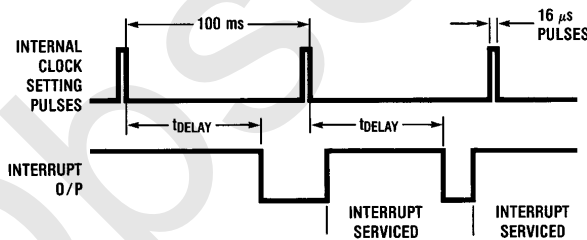
The technique below will detect both time changing *between* read strobes (i.e., between reading tens of minutes and units of hours) and also time changing *during* read, which can produce invalid data.

- 1) Read and store the value of the *lowest* order time register required.

- 2) Read out all the time registers required. The registers may be read out in any order, simplifying software requirements.

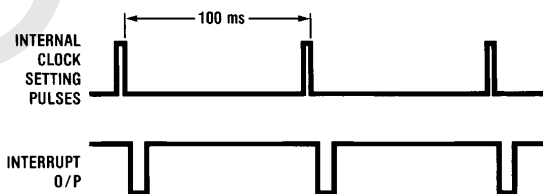
- 3) Read the lowest order register and compare it with the value stored previously in step 1. If it is still the same, then all time data is good. If it has changed, then store the new value and go back to step 2.

In general, the rule is that the first and last reads *must* both be of the lowest order time register. These two values can then be compared to ensure that no change has occurred. This technique works because for any higher order time register to change, all the lower order registers must also change. If the lowest order register does not change, then no higher order register has changed either.



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FIGURE A-1. Time Delay from Clock Setting Pulses to Interrupt is Constant

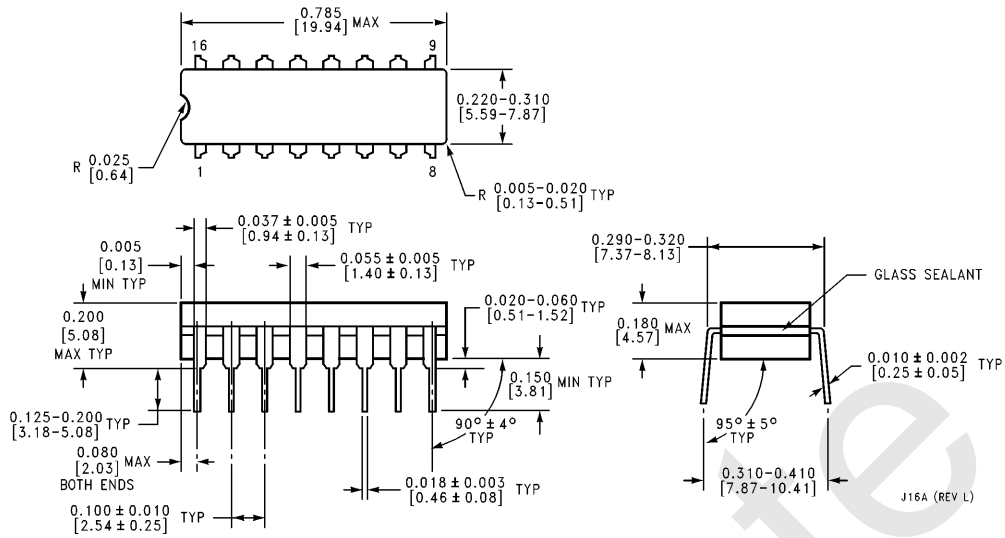


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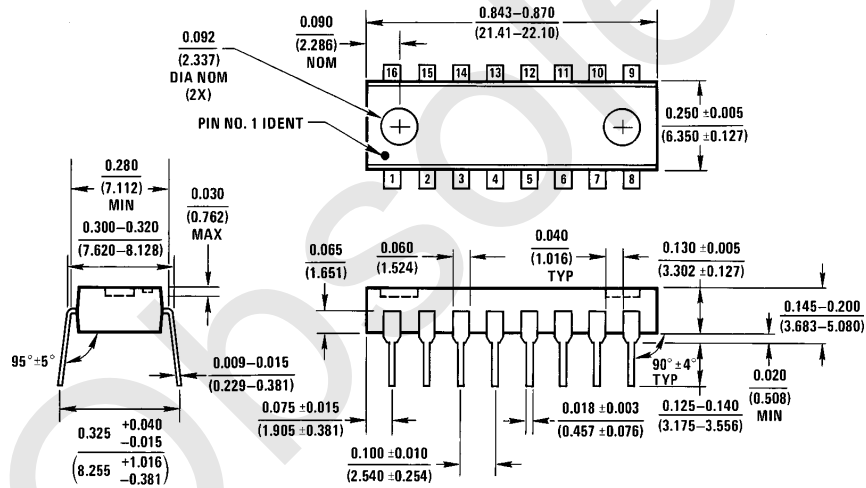
FIGURE A-2. Interrupt Timer Synchronized with Clock Setting Pulses

Obsolete

**Physical Dimensions** inches (millimeters)



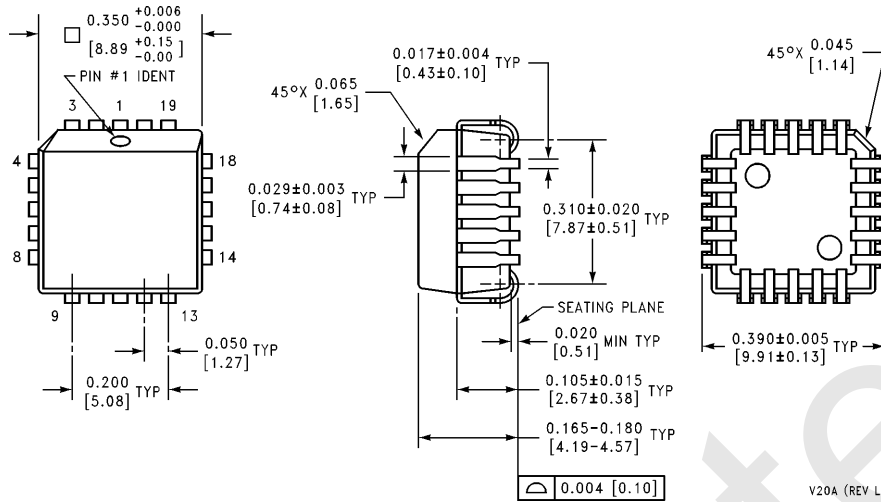
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**Order Number MM58274CJ**  
**NS Package Number J16A**



**Molded Dual-In-Line Package (N)**  
**Order Number MM58274CN**  
**NS Package Number N16A**



**Physical Dimensions** inches (millimeters) (Continued)



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**Order Number MM58274CV**  
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